

Notice of References Cited

Application/Control No.

10/520,798

Applicant(s)/Patent Under
Reexamination
SUN ET AL.

Examiner

DAVID W. SCHEUERMANN

Art Unit

2834

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 04078315 A	03-1992	Japan	TANAKA et al.	
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NON-PATENT DOCUMENTS

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